| Enrollment No: | Exam Seat No: | |
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| | C. U. SHAH UNIVERSITY | |
| | Summer Examination-2020 | |

Subject Name: VLSI Technology

Subject Code: 4TE07VLT1 Branch: B.Tech (EC)

Semester: 7 Date: 27/02/2020 Time: 10:30 To 01:30 Marks: 70

Instructions:

- (1) Use of Programmable calculator & any other electronic instrument is prohibited.
- (2) Instructions written on main answer book are strictly to be obeyed.
- (3) Draw neat diagrams and figures (if necessary) at right places.
- (4) Assume suitable data if needed.

| Q-1 | | Attempt the following questions | (14) |
|--------|------------|---|--------------|
| | a) | Draw the more simplified view of VLSI design flow. | |
| | b) | Discuss briefly term design hierarchy. | |
| | c) | Discuss briefly term regularity. | |
| | d) | Discuss briefly term modularity. | |
| | e) | Discuss briefly term locality. | |
| | f) | State the different VLSI design styles. | |
| | g) | State the names of components in typical FPGA chip. | |
| | h) | What is the difference between positive photoresist and negative photoresist? | |
| | i) | Why do we require device isolation between MOS transistors that comprise | |
| | | an IC? | |
| | j) | Discuss briefly short channel effect. | |
| | k) | Discuss briefly narrow channel effect. | |
| | 1) | Draw the three stage ring oscillator circuit consisting of identical inverts. | |
| | m) | Draw general layout of an H-tree clock distribution network. | |
| | n) | Discuss controllability in brief. | |
| Attemp | t any | four questions from Q-2 to Q-8 | |
| Q-2 | | Attempt all questions | (14) |
| | a) | Which are the four general criteria to measure design quality of a fabricated | 07 |
| | | integrated circuit (chip)? Briefly explain each of them. | |
| | b) | Discuss VLSI Design flow in detail with diagrams. | 07 |
| Q-3 | | Attempt all questions | (14) |
| | a) | Describe the process of fabrication of the NMOS transistor. | 07 |
| | b) | Discuss various packaging technology used for VLSI chips. | 07 |
| Q-4 | | Attempt all questions | (14) |
| | a) | Define threshold voltage (V _T) of MOSFET device. Which are the four | 07 |
| | | physical components on which V_T depends? Derive expression for V_T . | |
| | b) | What is the need of scaling? Discuss constant field scaling in detail with its | 07 |
| | | merits and demerits. | |
| Q-5 | | Attempt all questions | (14) |
| | a) | Draw CMOS Inverter circuit, Obtain expressions for V _{II} and V _{III} | 07 |



| | b) | Describe Elmore Delay technique to estimate the delay of interconnects. | 07 |
|------------|------------|--|-------------|
| Q-6 | | Attempt all questions | (14) |
| | a) | Explain the CMOS Transmission Gates (TGs). Draw eight-transistor CMOS – | 07 |
| | | TG implementation of the XOR function. | |
| | b) | Draw CMOS negative edge-triggered master-slave D flip-flop and explain its | 07 |
| | | working. | |
| Q-7 | | Attempt all questions | (14) |
| | a) | What is the need for voltage bootstrapping? Explain dynamic voltage | 07 |
| | | bootstrapping circuit with necessary mathematical analysis. | |
| | b) | What do you understand by clock skew? Explain various clock distribution | 07 |
| | | schemes with diagrams. | |
| Q-8 | | Attempt all questions | (14) |
| | a) | Discuss Ad hoc testable design techniques. | 07 |
| | b) | Explain Built-in Self Test (BIST) techniques with necessary diagrams. | 07 |

